

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10770295	CHANG ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Bétit, Jacob F	2164

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
updated search	6/11/07	JFB

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>